

<b>Notice of References Cited</b>	Application/Control No. 10/562,630	Applicant(s)/Patent Under Reexamination YOSHIDA, KYOHIRO	
	Examiner Xiaoliang Chen	Art Unit 2841	Page 1 of 2

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Application/Control No.

10/562,630

Applicant(s)/Patent Under

Reexamination

YOSHIDA, KYOHIRO

Examiner

Xiaoliang Chen

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